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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Matthias SLODOWSKI
Title: APPARATUS AND METHOD FOR THIN-LAYER METROLOGY
Appl. No.: 10/777,162
Filing Date: 02/13/2004
Examiner: Gordon J. Stock, Jr.
Art Unit: 2877
Confirmation No.: 5100

AMENDMENT AND REPLY UNDER 37 CFR 1.111

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This communication is responsive to the Non-Final Office Action dated December 19, 2006, concerning the above-referenced patent application.

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this document.

Remarks/Arguments begin on page 6 of this document.